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FQB6N60 / FQI6N60

600V N-Channel MOSFET

General Description

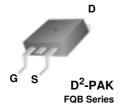
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

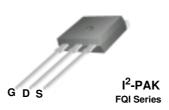
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supply.

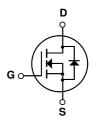
Features

- 6.2A, 600V, $R_{DS(on)} = 1.5\Omega$ @ $V_{GS} = 10$ V
- Low gate charge (typical 20 nC)
- Low Crss (typical 10 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQB6N60 / FQI6N60	Units
V _{DSS}	Drain-Source Voltage		600	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		6.2	Α
			3.9	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	24.8	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	440	mJ
I _{AR}	Avalanche Current	(Note 1)	6.2	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	13	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_{D}	Power Dissipation (T _A = 25°C) *		3.13	W
	Power Dissipation (T _C = 25°C)		130	W
	- Derate above 25°C		1.04	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

* When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.96	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
R _{θJA} Thermal Resistance, Junction-to-Ambient			62.5	°C/W

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.53		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V			10	μΑ
		$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3.1 A		1.2	1.5	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 3.1 A (Note 4)		6.0		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		770 95 10	1000 120 13	pF pF pF
	•			10	13	þi
	ing Characteristics	T				
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_D = 6.2 \text{ A},$		20	50	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		70	150	ns
t _{d(off)}	Turn-Off Delay Time	(Note 4, 5)		40	90	ns
t _f	Turn-Off Fall Time	, , ,		45	100	ns
Q _g	Total Gate Charge	$V_{DS} = 480 \text{ V}, I_{D} = 6.2 \text{ A},$		20	25	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V (Note 4, 5)		4.9		nC
Q _{gd}	Gate-Drain Charge	(100 4, 0)		9.4		nC
Drain-S	Source Diode Characteristics ar	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				6.2	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	ximum Pulsed Drain-Source Diode Forward Current			24.8	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 6.2 A		-	1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 6.2 \text{ A},$		290		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)		2.35		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 21 mH, $I_{AS} = 6.2A$, $V_{DD} = 50V$, $R_{G} = 25~\Omega$, Starting $T_{J} = 25^{\circ}C$ 3. $I_{SD} \leq 6.2A$, $di/dt \leq 200A/\mu s$, $V_{DD} \leq 8V_{DSS}$, Starting $T_{J} = 25^{\circ}C$ 4. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$ 5. Essentially independent of operating temperature

Typical Characteristics

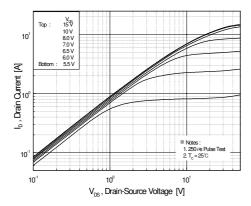


Figure 1. On-Region Characteristics

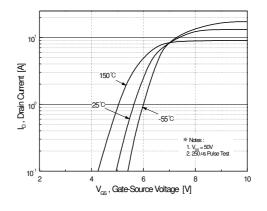


Figure 2. Transfer Characteristics

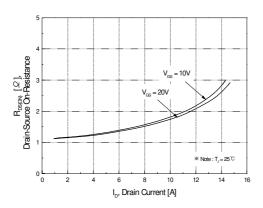


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

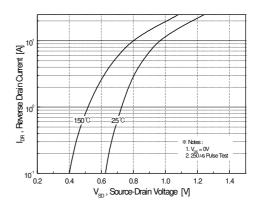


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

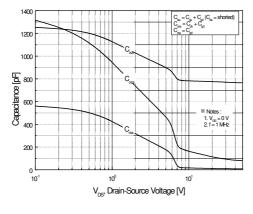


Figure 5. Capacitance Characteristics

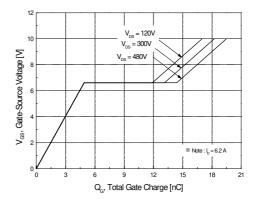


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

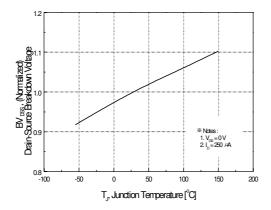
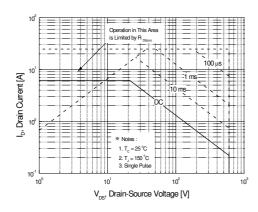


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



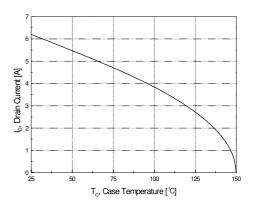


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

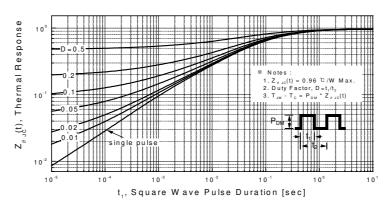
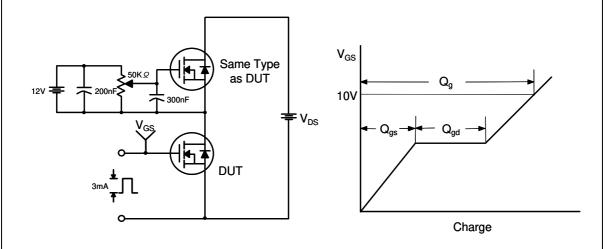


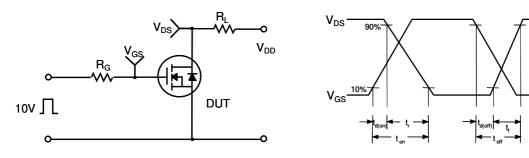
Figure 11. Transient Thermal Response Curve

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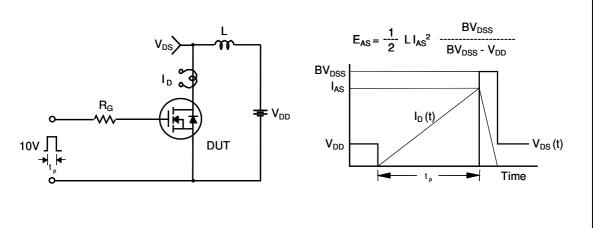
Gate Charge Test Circuit & Waveform



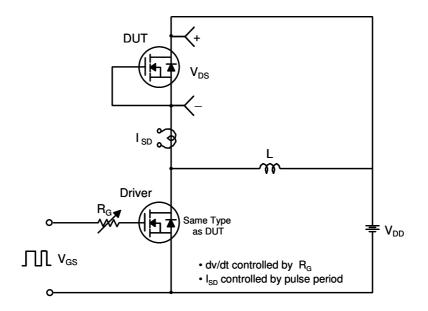
Resistive Switching Test Circuit & Waveforms

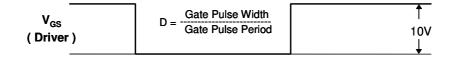


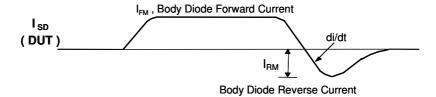
Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms







(DUT)

Body Diode Recovery dv/dt

Vsp.

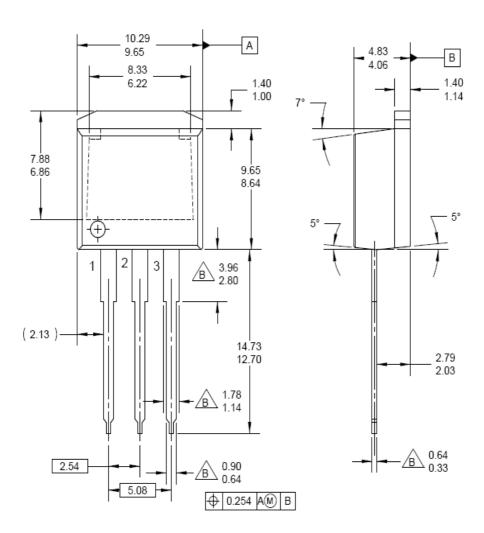
Body Diode Forward Voltage Drop

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Mechanical Dimensions D² - PAK -A-9.00 MIN 10.00 4.00 MIN (2.12) -1.50 MIN ♦ 0.25 M B AM 5.08 LAND PATTERN RECOMMENDATION -B--6.22 MIN-1.65 1.14 6.86 MIN 15.88 14.61 · SEE DETAIL A 0.25 0.10 B .25 MAX SEATING PLANE Dimensions in Millimeters

Mechanical Dimensions

I² - PAK



Dimensions in Millimeters





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